

Notice of References Cited	Application/Control No. 09/864,509	Applicant(s)/Patent Under Reexamination WHETSEL ET AL	
	Examiner Cynthia Britt	Art Unit 2133	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,311,302	10-2001	Cassetti et al.	714/727
	B	US-6,334,198	12-2001	Adusumilli et al.	714/727
	C	US-			
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	E	US-			
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	G	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Hierarchical Test Access Architecture for Embedded Cores in an Integrated Circuit" by Bhattacharya, D. VLSI Test Symposium Proceedings, Publication Date: 26-30 April 1998 pages 8-14 Inspec Accession Number: 6039765
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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